

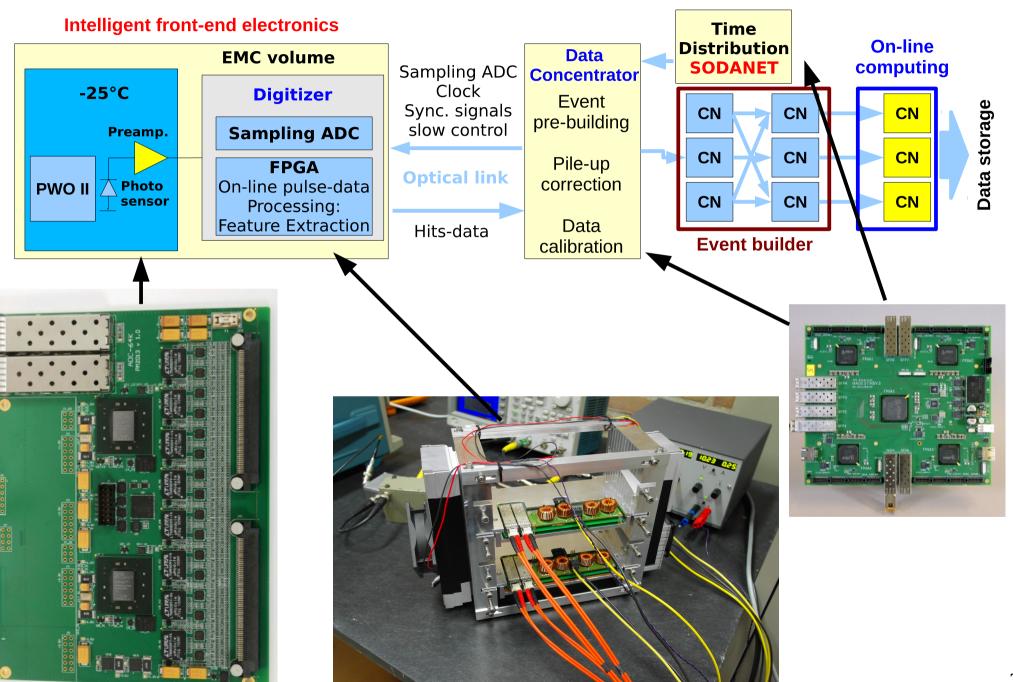
Overview of the EMC Readout

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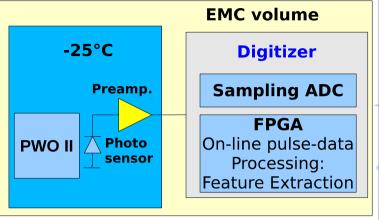
for the PANDA collaboration

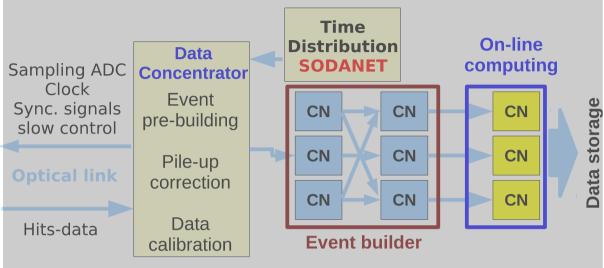
EMC Readout



EMC Front-End Electronics

Intelligent front-end electronics





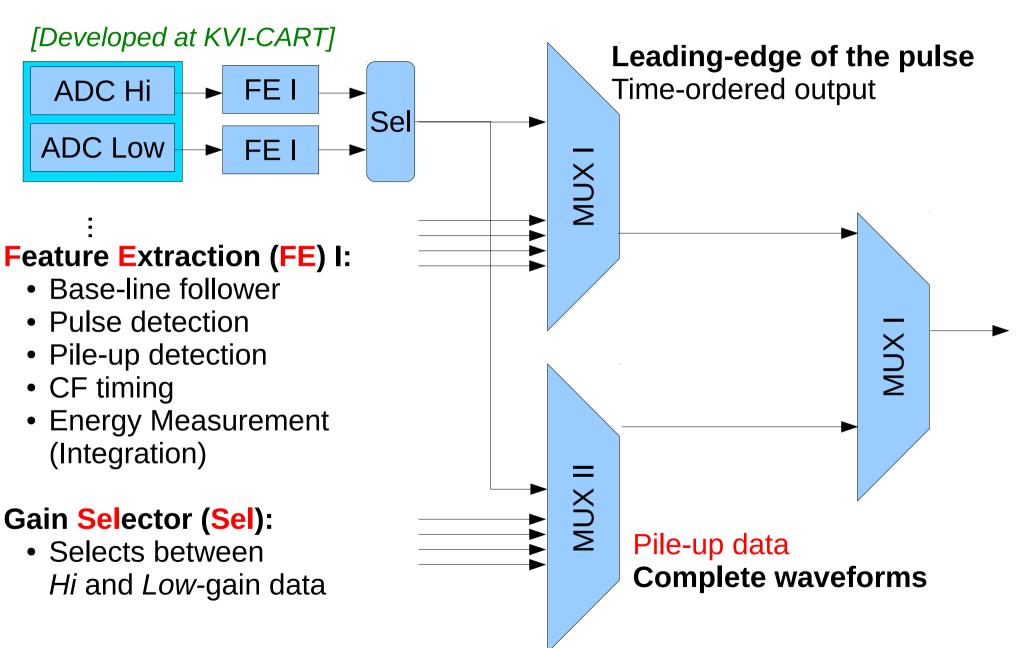


EMC digitizer:

- 64 ADC channels (32 dual-gain readout channels)
- 14 bit resolution
- 80-125 MHz sampling rate
- On-line detection of hits, extraction of hit information, pulse pile-up recovery by two Xilinx Kintex-7 FPGAs

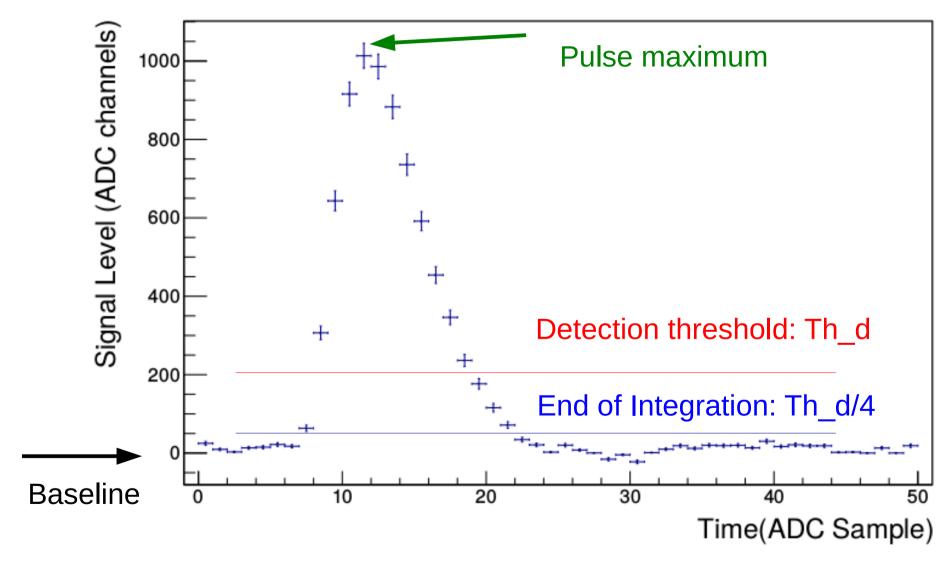
Digitizers are located in radiation area → precautions have to be taken against configuration changes and SEU in FPGAs

Feature-Extraction Algorithm



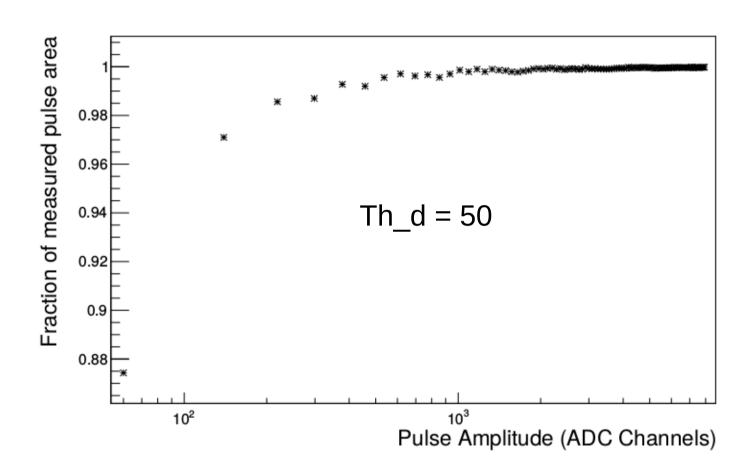
FE-I

ADC samples after base-line subtraction



Integration includes: one sample before Th_d till last sample above Th_d/4

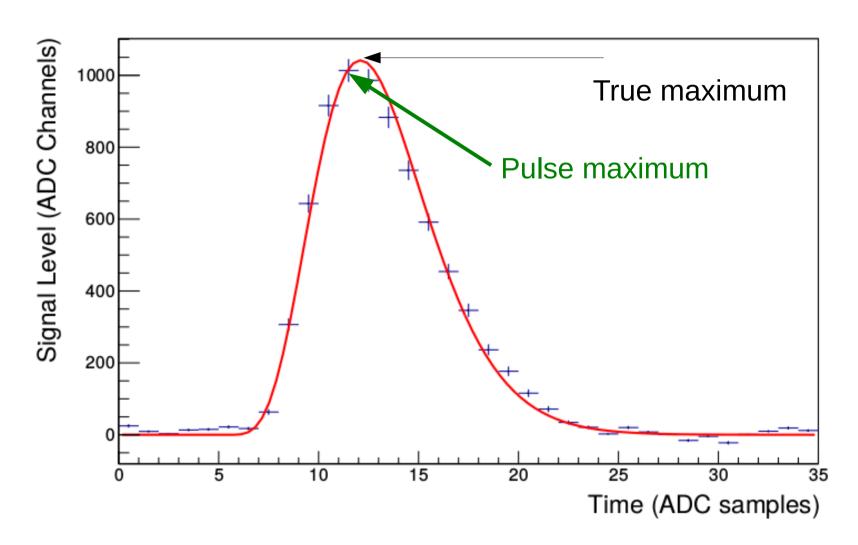
Pulse-Area Measurement



Summing samples above threshold:

- Reduces noise induced by ADC
- Not complete pulse-integration near threshold: Acceptable?

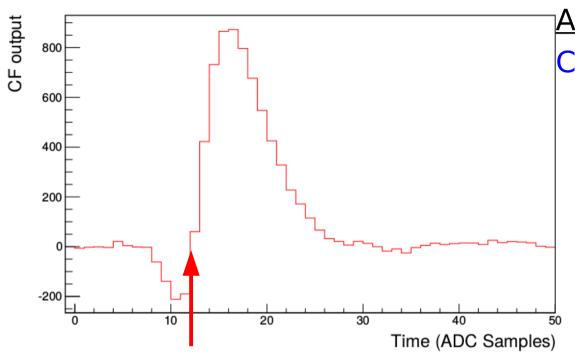
Precise Amplitude Measurement



Measured "maximum value" is always smaller than the pulse amplitude:

 Difference depends on pulse phase (fraction) between start of the pulse and phase of sampling clock

Time Measurement



Analogue-like implementation:

 $CFT(n) = MWD(n-d) - R \cdot MWD(n)$

- Delay d = signal rise time
- Fraction R to select most linear part of the signal leading edge (R=1/4)
- N number for the linear regression
- Symmetry against zero level

Time stamp: zero-crossing (linear regression)

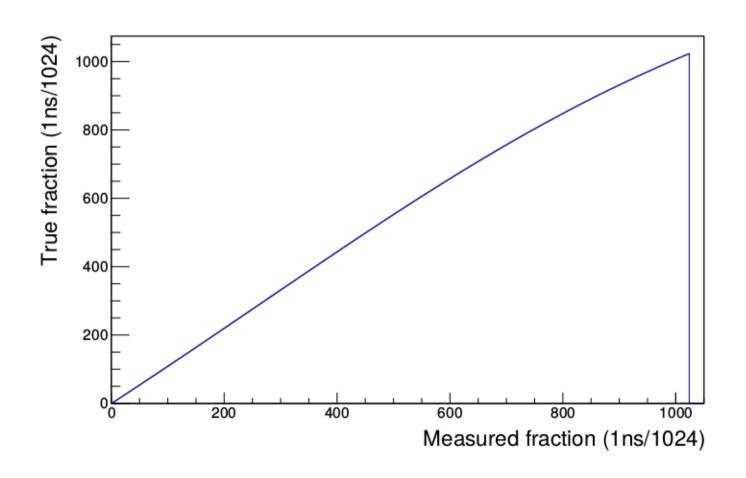
Linear regression induces some error in the time measurement



Has to be corrected

Time-Stamp Correction

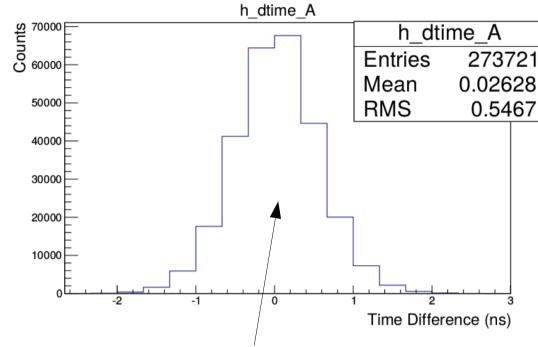
- A correction LUT is calculated using measured waveform
- Correction is performed at the data concentrator
- There is one LUT for one DC (channel-to-channel pulseshape variations can not be corrected)

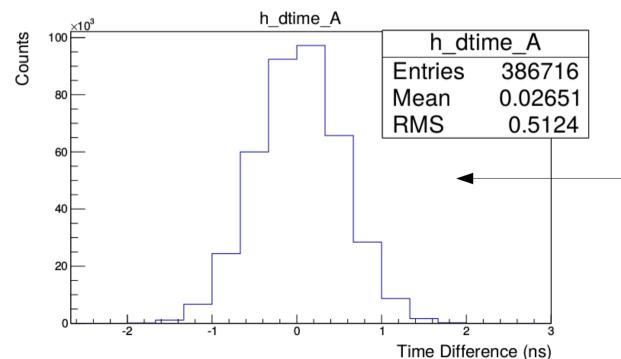


Correction in Action

Measurement with LED pulser and EMC proto

Time difference between two channels





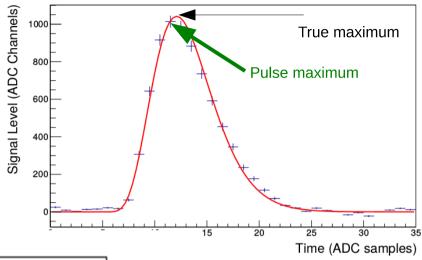


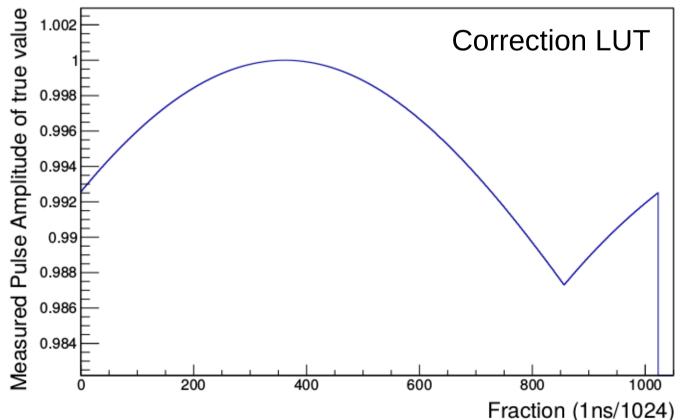
With on-line correction

It Works!

Correction for "Maximum"

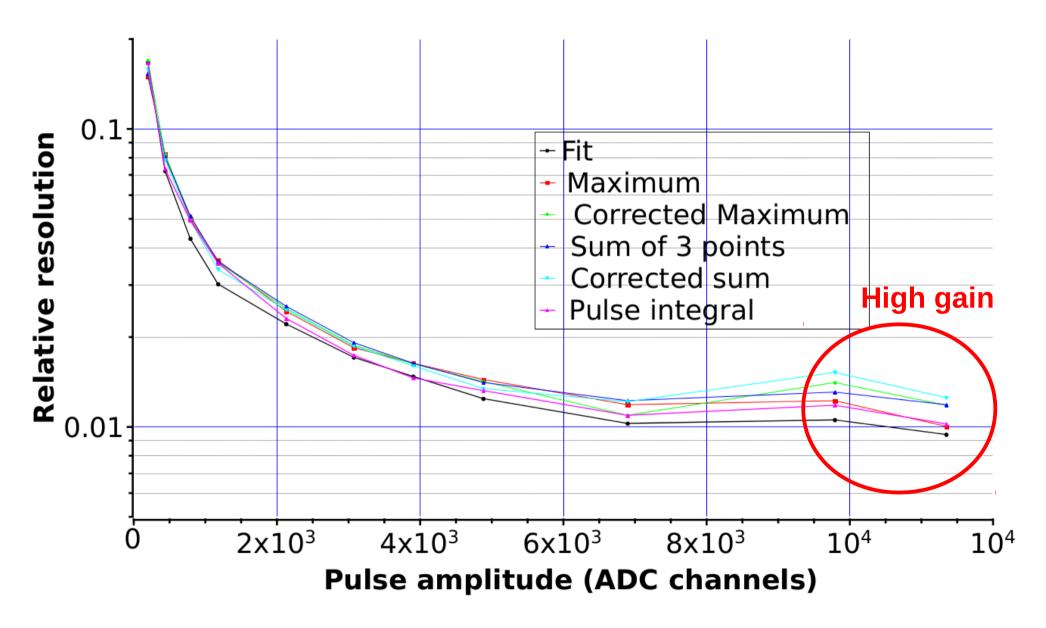
Correction LUT can be constructed to calculate true amplitude of a pulse





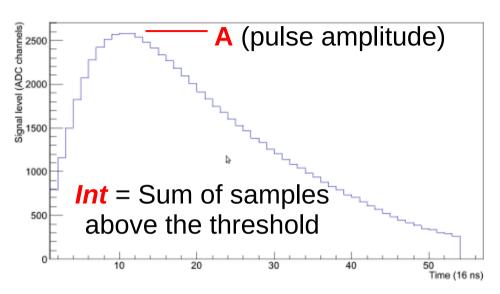
- No threshold effects as with "integration"
- Very sensitive to pulse shape (no gain in resolution for realistic case)

The Best "Energy" Measurement

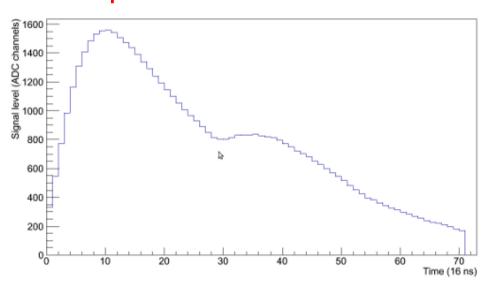


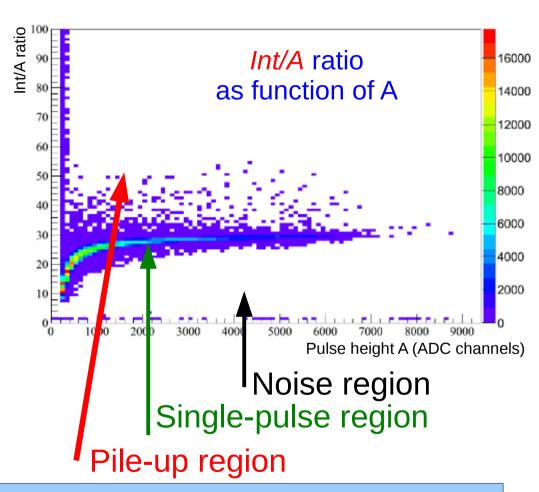
Pile-up Detection

If samples above threshold satisfy Int/A criterion \rightarrow Pulse is detected



Pile-up event identified on-line





Pulse-detection works properly:

Detection of single pulses
 Detection of pile-up structures

Data Concentrator

Implemented and tested:

- Time ordering of data from all inputs
- Packaging of the output data according to the SODANET protocol
- On-line data reduction (combing data from two different channels related to two LAAPDs, reading out one crystal; data-streams from two digitizers)
- On-line Calibration
- On-line correction of time-stamps (amplitudes)

To be done:

On-line pile-up recovery

Work in progress:

Change speed of synchronous optical links to 2 Gb/s



Expected Particle-Flux at FPGA Location

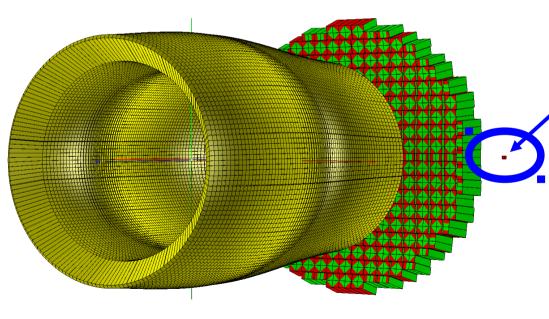
Monte Carlo input:

Flux of charged particles and neutrons

Hossein Moeini, Ganesh Tambave (KVI-CART)



(Pawel Marciniewski, U. Uppsala)



- FPGA on the EMC digitizer implemented in PANDAroot
- Estimated flux of charged particles: ~ 70 /s/cm²
- Neutron flux to be estimated by FLUKA simulations

Irradiation of Kintex-7 (XC7K325T)

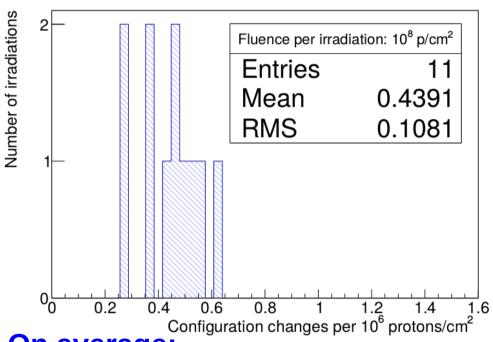
150 MeV protons, homogeneous field

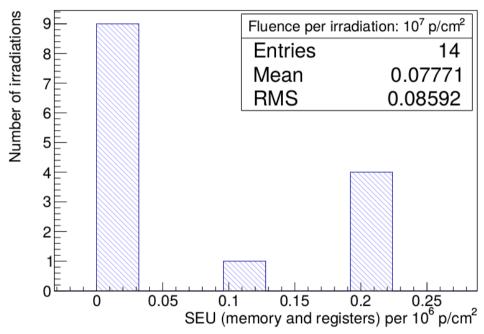
Resources involved in the SEU test: Registers: **54%** (=2.2·10⁵)

Block RAM: **86%** (=1.4·10⁴ kb)

Configuration changes per 10⁶ /cm²

SEU per 10⁶ /cm²





On average:

configuration changes: 0.44(11) per 10⁶ /cm²

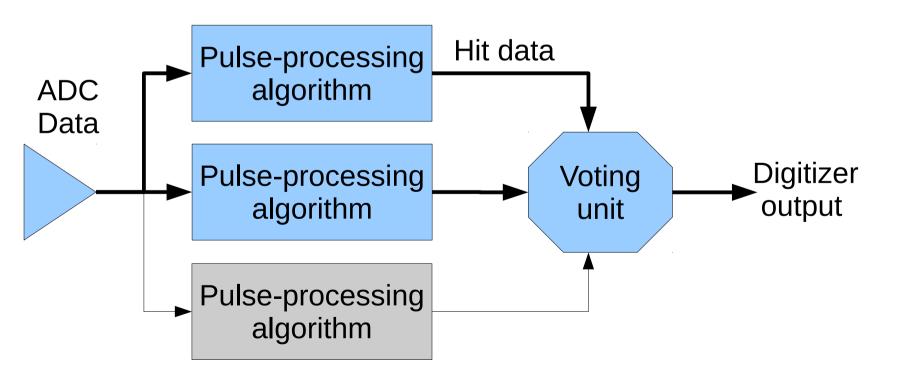
SEU events: 0.08(8) per 10⁶ /cm²

→54 min operation without reconfiguration (incl. safety factor 10)

Modular Triple Redundancy (MTR)

Current implementation contains double redundancy: in case of SEU, the output of one module will be corrupted. Measurement: ~ 2 ms recovery time after SEU error

→ Extend mean operation time of EMC digitizer in radiation environment: MTR: 3 identical implementations in FPGA. for the most sensitive modules of the data-processing algorithm



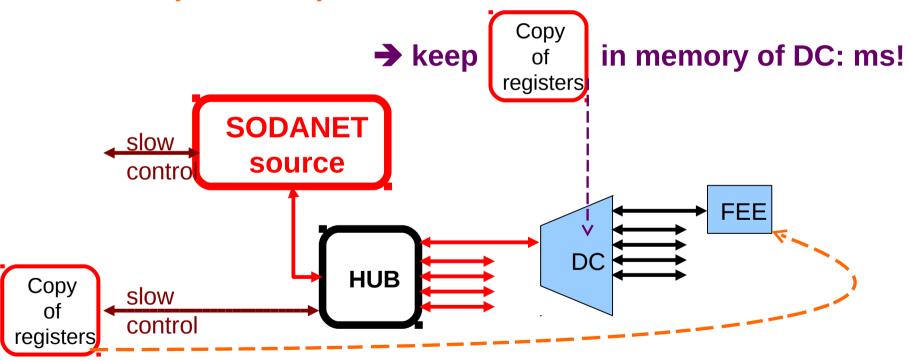
Recovery of EMC Digitizer

configuration change requires restart:

- reconfigure FPGA
- reprogram registers used by the on-line feature-extraction algorithm

Fast reprogramming is crucial for decreasing the dead time:

too slow (~seconds) via slow control



Together with a fast reload of configuration from a flash memory: implemented reboot procedure takes ~ 10 ms

Outlook

Feature extraction

 The algorithm is fixed, the pile-up recovery still has to be implemented in the data concentrator/digitizer

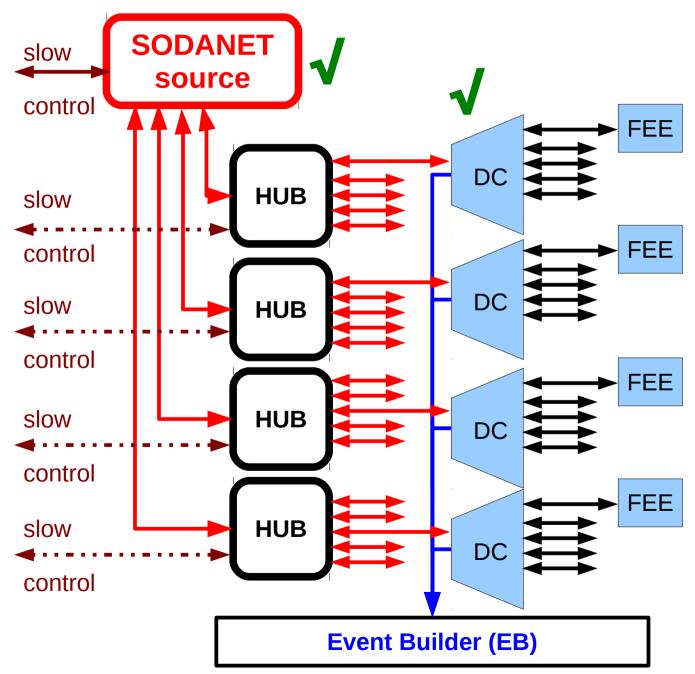
Radiation hardness

- Kintex-7 is less (X 3) prone to configuration changes
 even though it has X10 more resources
- Measurements reveal SEUs always together with configuration change → SEUs much less probable than configuration change
- Digitizer using standard FPGA can be used in PANDA EMC
- Modular Triple Redundancy is feasible for data-processing
 → will be implemented in next revision of EMC digitizer
- Fast reboot of the EMC digitizer (~10 ms) lowers dead-time of the readout system

Next steps:

- Test readout with external SODA source, connect FEE with burst-building network (CN): beginning of 2015
- Irradiate "Kintex" version of the digitizer

SODANET Topology



SODANET link:

- Bidirectional
- Synchronous (only in one direction)
- Transfer:
 - source → DC: synchronization information and FEE configuration
 - DC → source: slow control, used for time calibration

Data link (DC → EB):

 Unidirectional Ethernet

Link DC ↔ **FEE**:

- Bidirectional, synchronous
- Protocol up to subsystem

Crate

